

ATTY DOCKET NO.

2270-0042

APPLICATION NO

10/007,100

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Sakamoto et al.

FILING DATE

December 6, 2001

GROUP

2633

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	A01	6,275,314	08/14/01	Ishikawa et al.	—	—	—
	A02	6,252,688	06/26/01	Ishikawa et al.	—	—	—
	A03	6,252,687	06/26/01	Ishikawa et al.	—	—	—
	A04	6,243,176	06/05/01	Ishikawa et al.	—	—	—
	A05	5,696,614	12/09/97	Ishikawa et al.	—	—	—
	A06	5,636,046	06/03/97	Ishikawa et al.	—	—	—
	A07	5,612,807	03/18/97	Ishikawa et al.	—	—	—
	A08	5,602,666	02/11/97	Ishikawa et al.	—	—	—
	A09	5,559,910	09/24/96	Taga et al.	—	—	—
	A10	5,410,624	04/25/95	Morkel	—	—	—
	A11	20010028489	10/11/01	Ishikawa et al.	—	—	—
DS	A12	20010022676	09/20/01	Ishikawa et al.	—	—	—

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
DS	B01	JP 2003179550	06/27/03	Japan				X
	B02	JP 3396441	04/14/03	Japan				X
	B03	JP 3396270	04/14/03	Japan				X
	B04	JP 11317705	11/16/99	Japan				X
	B05	JP 11313045	11/09/99	Japan				X
	B06	JP 7336301	12/22/95	Japan				X
	B07	JP 7107069	04/21/95	Japan				X
DS	B08	GB 2281670	03/08/95	Great Britain				X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	C01	
	C02	
	C03	

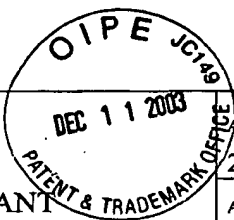
EXAMINER

Dalzid Singh

DATE CONSIDERED

12/16/04

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LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY DOCKET NO.	APPLICATION NO
	2270-042-999	10/007,100
	APPLICANT SAKAMOTO et al.	
	FILING DATE December 6, 2001	GROUP 2633

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	A01	JP 05-110517	04/30/93	Japanese Unexamined Patent Application w/ English Abstract	—	—	—
DS	A02	JP 07-38531	02/07/95	Japanese Unexamined Patent Application w/ English Abstract	—	—	—
DS	A03	JP 07-66779	03/10/95	Japanese Unexamined Patent Application w/ English Abstract	RECEIVED DEC 17 2003 Technology Center 2600		
DS	A04	JP 08-288930	11/01/96	Japanese Unexamined Patent Application w/ English Abstract			
	A05						
	A06						
	A07						
	A08						

FOREIGN PATENT DOCUMENTS

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							YES	NO
	B01							
	B02							
	B03							
	B04							
	B05							

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	C02	
	C03	

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	A02						
	A03						
	A04						
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	A06						
	A07						
	A08						
	A09						

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
DS	B01	05-110517	4/30/93	Japan w/ English Abstract				X
DS	B02	06-090224	3/29/94	Japan w/ English Abstract				X
	B03							
	B04							
	B05							

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